


<b>Search Notes</b>  	<b>Application/Control No.</b>  10569714	<b>Applicant(s)/Patent Under Reexamination</b>  MEYER ET AL.
	<b>Examiner</b>  Chen, Catheryne	<b>Art Unit</b>  1655

SEARCHED			
Class	Subclass	Date	Examiner
none	none	1/22/08	CC

SEARCH NOTES		
Search Notes	Date	Examiner
INVENTOR NAME, USPT, PGPB, JPAB, EPAB, DWPI, MEDLINE, EMBASE, BIOSIS, CAPLUS, REGISTRY	1/22/08	CC
updated search	10/20/08	CC
updated search	11/2/09	CC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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